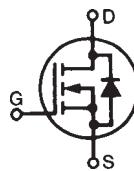


High Voltage Power MOSFET

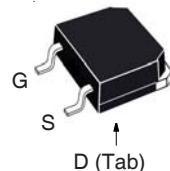
IXTT1N250HV



N-Channel Enhancement Mode
Fast Intrinsic Diode

V_{DSS} = 2500V
I_{D25} = 1.5A
R_{DS(on)} ≤ 40Ω

TO-268S



G = Gate D = Drain
S = Source Tab = Drain

Symbol	Test Conditions	Maximum Ratings		
V _{DSS}	T _J = 25°C to 150°C	2500	V	
V _{DGR}	T _J = 25°C to 150°C, R _{GS} = 1MΩ	2500	V	
V _{GSS}	Continuous	±20	V	
V _{GSM}	Transient	±30	V	
I _{D25}	T _C = 25°C	1.5	A	
I _{DM}	T _C = 25°C, Pulse Width Limited by T _{JM}	6	A	
P _D	T _C = 25°C	250	W	
T _J		- 55 ... +150	°C	
T _{JM}		150	°C	
T _{stg}		- 55 ... +150	°C	
T _L	1.6mm (0.062 in.) From Case for 10s	300	°C	
T _{SOLD}	Plastic Body for 10s	260	°C	
Weight		4	g	

Features

- High Blocking Voltage
- High Voltage Package
- Fast Intrinsic Diode
- Low Package Inductance

Advantages

- Easy to Mount
- Space Savings
- High Power Density

Symbol	Test Conditions (T _J = 25°C, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
BV _{DSS}	V _{GS} = 0V, I _D = 250μA	2500		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	2.0		V
I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V			±100 nA
I _{DSS}	V _{DS} = 0.8 • V _{DSS} , V _{GS} = 0V T _J = 125°C		25	μA
R _{DS(on)}	V _{GS} = 10V, I _D = 0.5 • I _{D25} , Note 1		40	Ω

Applications

- High Voltage Power Supplies
- Capacitor Discharge
- Pulse Circuits

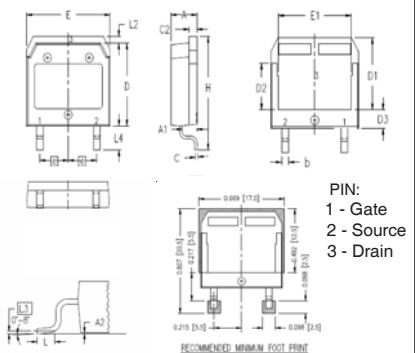
Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
g_{fs}	$V_{DS} = 50\text{V}$, $I_D = 0.5\text{A}$, Note 1	1.0	1.8	mS
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$	1660		pF
		77		pF
		23		pF
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Resistive Switching Times $V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 1\text{A}$ $R_G = 5\Omega$ (External)	69		ns
		25		ns
		132		ns
		39		ns
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10\text{V}$, $V_{DS} = 600\text{V}$, $I_D = 0.5\text{A}$	41		nC
		8		nC
		16		nC
R_{thJC}			0.50	$^\circ\text{C}/\text{W}$
R_{thCS}		0.21		$^\circ\text{C}/\text{W}$

Source-Drain Diode

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
I_s	$V_{GS} = 0\text{V}$		1.5	A
I_{SM}	Repetitive, Pulse Width Limited by T_{JM}		6	A
V_{SD}	$I_F = 1\text{A}$, $V_{GS} = 0\text{V}$, Note 1		1.5	V
t_{rr}	$I_F = 1\text{A}$, $-di/dt = 100\text{A}/\mu\text{s}$, $V_R = 200\text{V}$	2.5		μs

Note 1. Pulse test, $t \leq 300\mu\text{s}$, duty cycle, $d \leq 2\%$.

TO-268 (VHV) Outline



SYM	INCHES		MILLIMETER	
	MIN	MAX	MIN	MAX
A	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
A2	.001	.010	0.02	0.25
b	.045	.057	1.15	1.45
C	.016	.026	0.40	0.65
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.465	.476	11.80	12.10
D2	.295	.307	7.50	7.80
D3	.114	.126	2.90	3.20
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
E2	.215	BSC	5.45	BSC
H	.736	.752	18.70	19.10
L	.067	.079	1.70	2.00
L2	.039	.045	1.00	1.15
L3	.010	BSC	0.25	BSC
L4	.150	.161	3.80	4.10

ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 7,005,734 B2 7,157,338B2 4,860,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405 B2 6,759,692 7,063,975 B2 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2 7,071,537

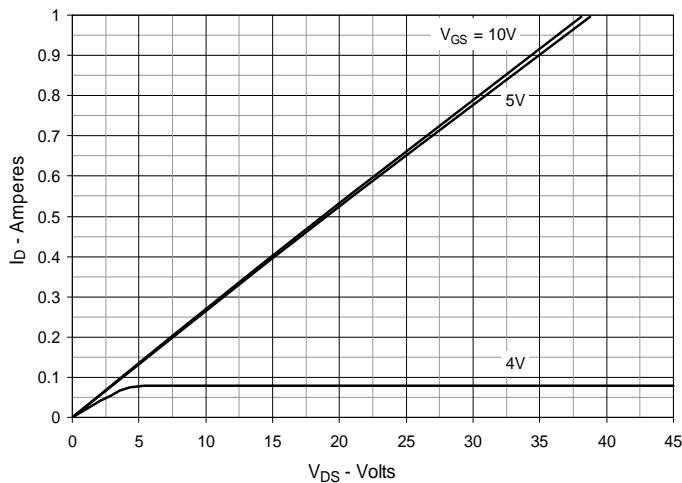
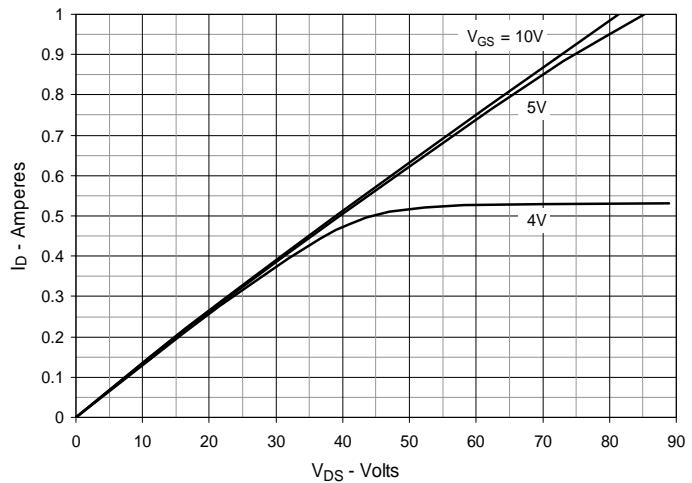
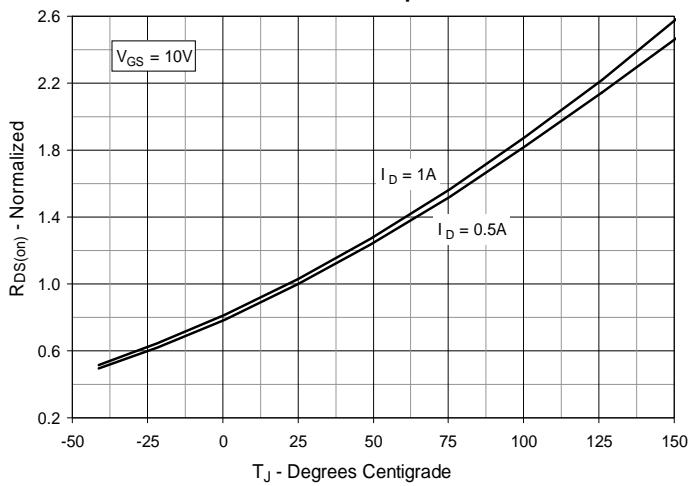
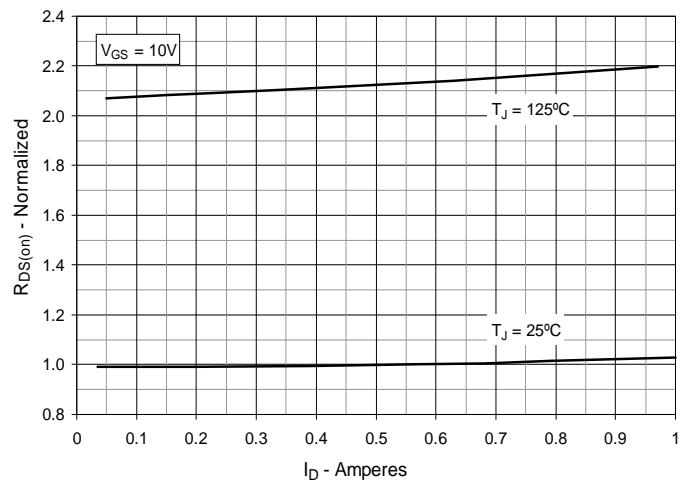
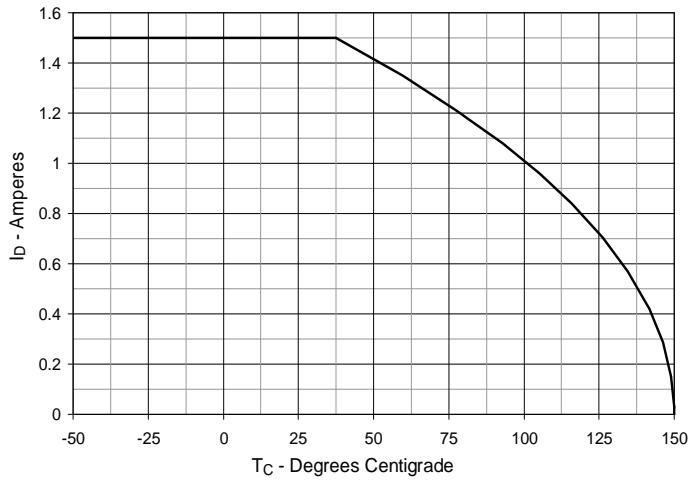
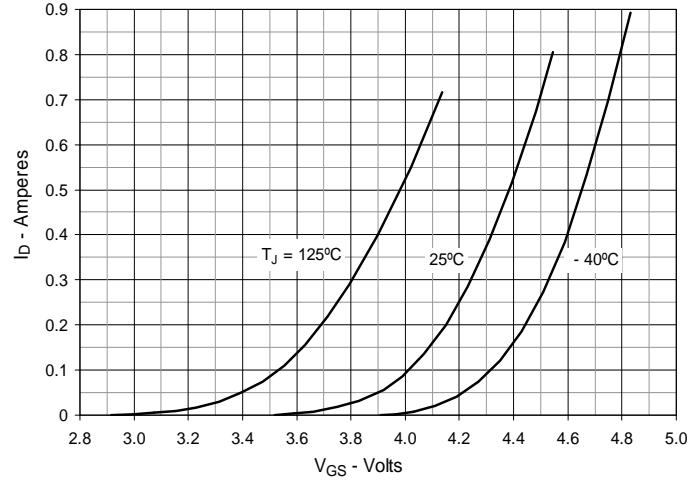
Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$

Fig. 2. Output Characteristics @ $T_J = 125^\circ\text{C}$

Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 0.5\text{A}$ Value vs. Junction Temperature

Fig. 3. $R_{DS(on)}$ Normalized to $I_D = 0.5\text{A}$ Value vs. Drain Current

Fig. 5. Maximum Drain Current vs. Case Temperature

Fig. 6. Input Admittance


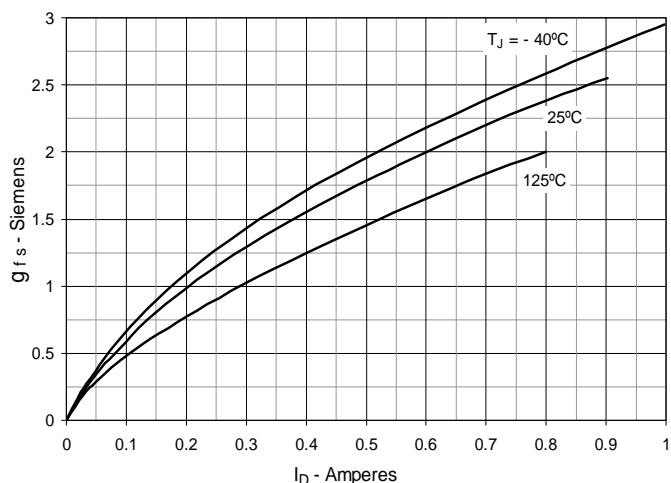
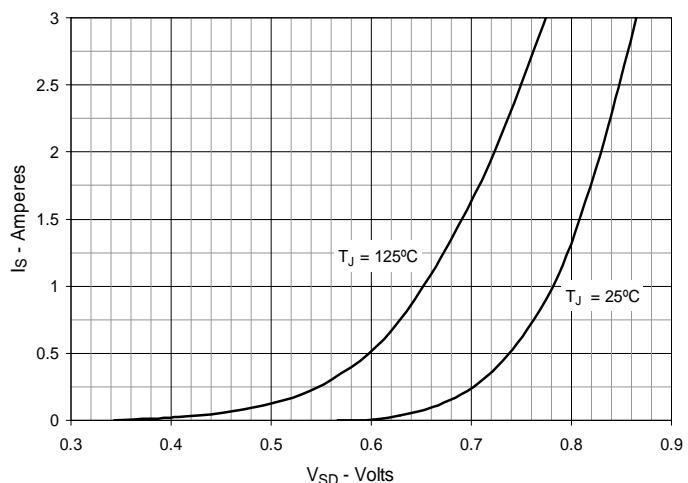
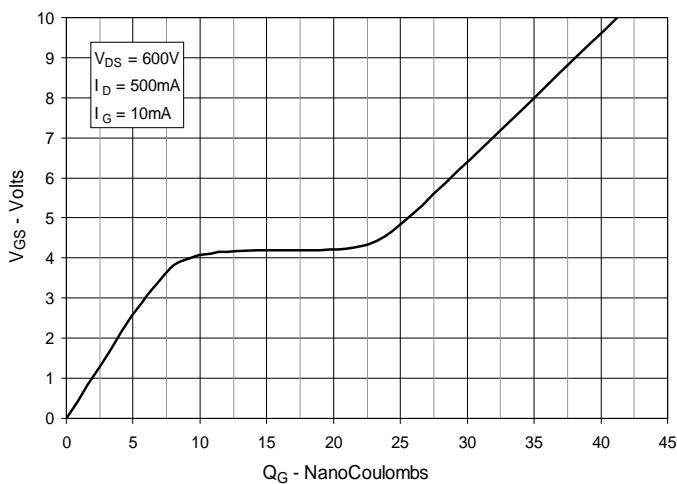
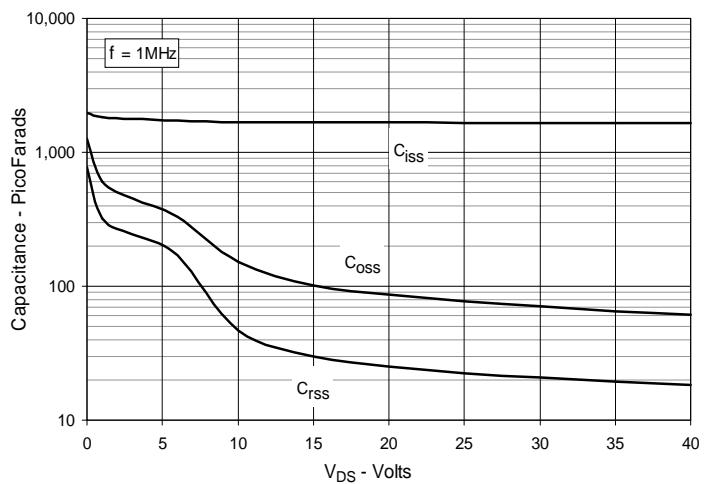
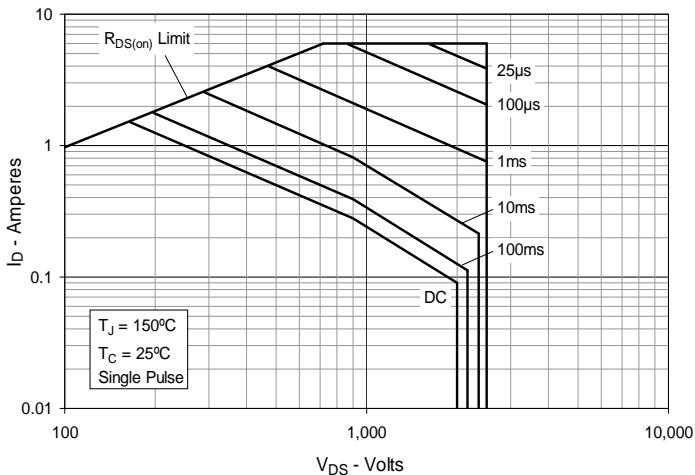
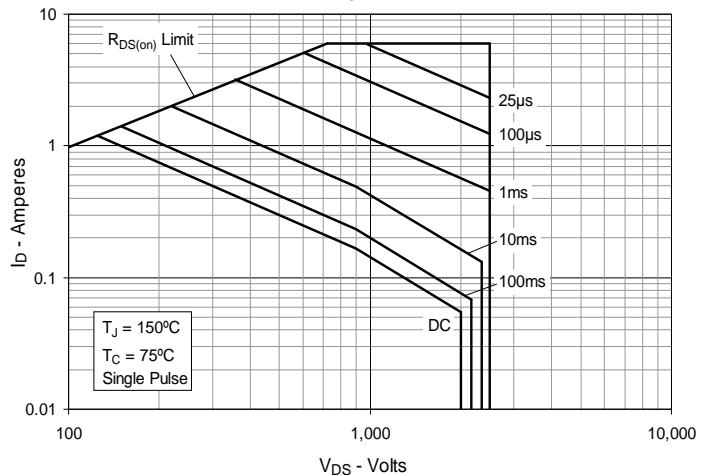
Fig. 7. Transconductance

Fig. 8. Forward Voltage Drop of Intrinsic Diode

Fig. 9. Gate Charge

Fig. 10. Capacitance

**Fig. 11. Forward-Bias Safe Operating Area
@ $T_C = 25^\circ\text{C}$**

**Fig. 12. Forward-Bias Safe Operating Area
@ $T_C = 75^\circ\text{C}$**


Fig. 13. Maximum Transient Thermal Impedance